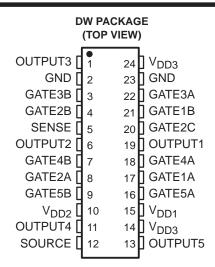
- Low  $r_{DS(on)}$ : 0.1  $\Omega$  Typ (Full H-Bridge) 0.4  $\Omega$  Typ (Triple Half H-Bridge)
- Pulsed Current:
  - 12 A Per Channel (Full H-Bridge) 6 A Per Channel (Triple Half H-Bridge)
- Matched Sense Transistor for Class A-B Linear Operation
- Fast Commutation Speed

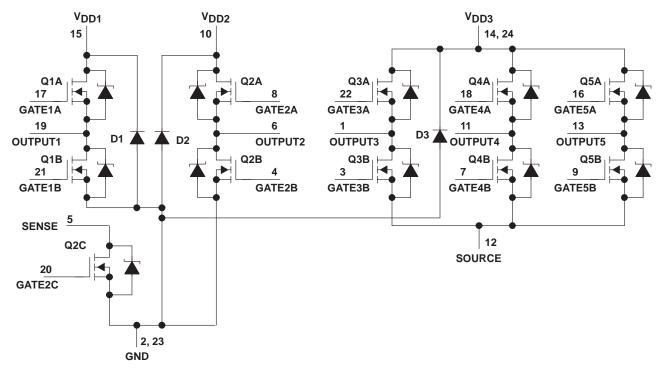
### description

The TPIC1501A is a monolithic power array that consists of ten electrically isolated N-channel enhancement-mode power DMOS transistors, four of which are configured as a full H-bridge and six as a triple half H-bridge. The lower stage of the full H-bridge features an integrated sense FET to allow biasing of the bridge in class A-B operation.



The TPIC1501A is offered in a 24-pin wide-body surface-mount (DW) package and is characterized for operation over the case temperature range of -40°C to 125°C.

### schematic



NOTES: A. Pins 2 and 23 must be externally connected.

- B. Pins 14 and 24 must be externally connected.
- C. No output may be taken greater than 0.5 V below GND.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



# absolute maximum ratings, $T_C = 25^{\circ}C$ (unless otherwise noted)<sup>†</sup>

Supply-to-GND voltage
Source-to-GND voltage (Q3A, Q4A, Q5A)
Output-to-GND voltage
Sense-to-GND voltage
Gate-to-source voltage range, VGS (Q1A, Q1B, Q2A, Q2B, Q3A, Q3B, Q4A, Q4B, Q5A, Q5B) ±20 V
Gate-to-source voltage range, V <sub>GS</sub> (Q2C)
Continuous drain current, each output (Q1A, Q1B, Q2A, Q2B)
Continuous drain current, each output (Q3A, Q3B, Q4A, Q4B, Q5A, Q5B)
Continuous drain current (Q2C)
Continuous source-to-drain diode current (Q1A, Q1B, Q2A, Q2B)
Continuous source-to-drain diode current (Q3A, Q3B, Q4A, Q4B, Q5A, Q5B) 1.5 A
Continuous source-to-drain diode current (Q2C)
Pulsed drain current, each output, I <sub>max</sub> (Q1A, Q1B, Q2A, Q2B) (see Note 1 and Figure 24) 12 A
Pulsed drain current, each output, I <sub>max</sub> (Q3A, Q3B, Q4A, Q4B, Q5A, Q5B)
(see Note 1 and Figure 25) 6 A
Pulsed drain current, I <sub>max</sub> (Q2C) (see Note 1)
Continuous total power dissipation, $T_C = 70^{\circ}C$ (see Note 2 and Figures 24 and 25)
Operating virtual junction temperature range, T <sub>J</sub>
Operating case temperature range, T <sub>C</sub>
Storage temperature range, T <sub>stg</sub>
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. Pulse duration = 10 ms, duty cycle = 2%
  - 2. Package is mounted in intimate contact with infinite heat sink.



# electrical characteristics, Q1A, Q1B, Q2A, Q2B, $T_C = 25^{\circ}C$ (unless otherwise noted)

		1					
	PARAMETER	TEST CON	MIN	TYP	MAX	UNIT	
V(BR)DSX	Drain-to-source breakdown voltage	$I_D = 250 \mu A$ ,	V <sub>GS</sub> = 0	20			V
VGS(th)	Gate-to-source threshold voltage	I <sub>D</sub> = 1 mA, See Figure 5	$V_{DS} = V_{GS}$	1.4	1.7	2.1	V
VGS(th)match	Gate-to-source threshold voltage matching	I <sub>D</sub> = 1 mA,	$V_{DS} = V_{GS}$			40	mV
V <sub>(BR)</sub>	Reverse drain-to-GND breakdown voltage	Drain-to-GND curren (D1, D2)	t = 250 μA	20			V
V <sub>DS(on)</sub>	Drain-to-source on-state voltage	I <sub>D</sub> = 2 A, See Notes 3 and 4	V <sub>GS</sub> = 10 V,		0.2	0.24	V
VF	Forward on-state voltage, GND-to-V <sub>DD1</sub> , GND-to-V <sub>DD2</sub>	I <sub>D</sub> = 3 A (D1, D2) See Notes 3 and 4			1.8		V
V	Forward on otata valtage accuracy to ducin	I <sub>S</sub> = 2 A, See Notes 3 and 4 ar	V <sub>GS</sub> = 0, nd Figure 19		0.85	1.05	V
VF(SD)	Forward on-state voltage, source-to-drain	I <sub>S</sub> = 3 A, See Notes 3 and 4 ar	V <sub>GS</sub> = 0, nd Figure 19		0.9	1.1	V
	Zana mata waltana duala awanat	V <sub>DS</sub> = 16 V,	T <sub>C</sub> = 25°C		0.05	1	^
IDSS	Zero-gate-voltage drain current	VGS = 0	T <sub>C</sub> = 125°C		0.5	10	μΑ
IGSSF	Forward-gate current, drain short circuited to source	V <sub>GS</sub> = 16 V,	V <sub>DS</sub> = 0		10	100	nA
IGSSR	Reverse-gate current, drain short circuited to source	V <sub>SG</sub> = 16 V,	V <sub>DS</sub> = 0		10	100	nA
l	Leakage current, V <sub>DD1</sub> -to-GND,	V <sub>DGND</sub> = 16 V	T <sub>C</sub> = 25°C		0.05	1	
llkg	V <sub>DD2</sub> -to-GND, gate shorted to source	VDGND = 10 V	T <sub>C</sub> = 125°C	0.5		10	μΑ
	Static drain-to-source on-state resistance	$V_{GS} = 10 \text{ V},$ $I_{D} = 2 \text{ A},$	T <sub>C</sub> = 25°C		0.1	0.12	
IDS(on)		See Notes 3 and 4 and Figure 9	T <sub>C</sub> = 125°C		0.14	0.18	Ω
rDS(on)	Statio drain to source on state resistance	$V_{GS} = 10 \text{ V},$ $I_{D} = 3 \text{ A},$	T <sub>C</sub> = 25°C		0.1	0.12	32
		See Notes 3 and 4 and Figures 7 and 9	T <sub>C</sub> = 125°C		0.14	0.18	
	Command transport directions	V <sub>DS</sub> = 14 V, See Notes 3 and 4	I <sub>D</sub> = 1 A,	1.5	2.5		6
9fs	Forward transconductance	V <sub>DS</sub> = 14 V, See Notes 3 and 4 ar	I <sub>D</sub> = 1.5 A, nd Figure 13	2	3.1		S
C <sub>iss</sub>	Short-circuit input capacitance, common source				240		
C <sub>oss</sub>	Short-circuit output capacitance, common source	V <sub>DS</sub> = 14 V, f = 1 MHz,	V <sub>GS</sub> = 0, See Figure 17		170		pF
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source	1		-	130		
$\alpha_{S}$	Sense-FET drain current ratio	V <sub>DS</sub> = 6 V,	$I_{D(Q2C)} = 40 \mu A$	75	130	200	

NOTES: 3. Technique should limit  $T_J - T_C$  to 10°C maximum.



<sup>4.</sup> These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

# TPIC1501A QUAD AND HEX POWER DMOS ARRAY

SLIS046A - MAY 1995 - REVISED JUNE 1996

# source-to-drain diode characteristics, Q1A, Q2A, $T_C = 25^{\circ}C$

	PARAMETER	TEST CO	MIN	TYP	MAX	UNIT	
t <sub>rr</sub>	Reverse-recovery time	Is = 1.5 A,	VGS = 0,		70		ns
Q <sub>RR</sub>	Total diode charge	V <sub>DS</sub> = 14 V, See Figures 1 and 23	di/dt = 100 A/μs,		90		nC
t <sub>rr</sub>	Reverse-recovery time	I <sub>S</sub> = 2 A,	V <sub>G</sub> S = 0,		75		ns
Q <sub>RR</sub>	Total diode charge	$V_{DS} = 14 \text{ V},$	$di/dt = 100 A/\mu s$		110		nC

# resistive-load switching characteristics, Q1A, Q1B, Q2A, Q2B, $T_C$ = 25°C

	PARAMETER		TEST CONDITIONS				MAX	UNIT												
t <sub>d</sub> (on)	Turn-on delay time					20														
td(off)	Turn-off delay time	V <sub>DD</sub> = 14 V,	$R_{L} = 9.3 \Omega$ ,	$t_{en} = 10 \text{ ns},$		30		200												
t <sub>r</sub>	Rise time	t <sub>dis</sub> = 10 ns, See Figure 3		15		ns														
tf	Fall time	1				25														
Qg	Total gate charge					5.6	7													
Q <sub>gs(th)</sub>	Threshold gate-to-source charge				V <sub>DS</sub> = 14 V, See Figure 4									V <sub>DS</sub> = 14 V, See Figure 4		$V_{GS} = 10 V$ ,		0.8	1	nC
Q <sub>gd</sub>	Gate-to-drain charge	guio i				1.4	1.75													
L(drain)	Internal drain inductance					5		nH												
L <sub>(source)</sub>	Internal source inductance					5		ПП												
r(gate)	Internal gate resistance			·		0.25		Ω												

# electrical characteristics, Q3A, Q3B, Q4A, Q4B, Q5A, Q5B, $T_C$ = 25°C (unless otherwise noted)

	PARAMETER	TEST COND	MIN	TYP	MAX	UNIT	
V(BR)DSX	Drain-to-source breakdown voltage	I <sub>D</sub> = 250 μA,	V <sub>GS</sub> = 0 V	20			V
VGS(th)	Gate-to-source threshold voltage	I <sub>D</sub> = 1 mA, See Figure 6	$V_{DS} = V_{GS}$	1.4	1.7	2.1	V
VGS(th)match	Gate-to-source threshold voltage matching	$I_D = 1 \text{ mA},$	$V_{DS} = V_{GS}$			40	mV
V <sub>(BR)</sub>	Reverse drain-to-GND breakdown voltage	Drain-to-GND current	= 250 μA (D3)	20			V
V <sub>DS(on)</sub>	Drain-to-source on-state voltage	I <sub>D</sub> = 1.5 A, See Notes 3 and 4	V <sub>GS</sub> = 10 V,		0.6	0.68	V
VF	Forward on-state voltage, GND-to-V <sub>DD3</sub>	I <sub>D</sub> = 1.5 A (D3) See Notes 3 and 4			1.7		V
V	Francisco de la contraction de	I <sub>S</sub> = 1.5 A, See Notes 3 and 4 and	V <sub>GS</sub> = 0, d Figure 20		1	1.2	V
VF(SD)	Forward on-state voltage, source-to-drain	I <sub>S</sub> = 2 A, See Notes 3 and 4 and	V <sub>GS</sub> = 0, d Figure 20		1.1	1.3	V
		V <sub>DS</sub> = 16 V,	T <sub>C</sub> = 25°C		0.05	1	•
IDSS	Zero-gate-voltage drain current	V <sub>GS</sub> = 0	T <sub>C</sub> = 125°C		0.5	10	μΑ
IGSSF	Forward-gate current, drain short circuited to source	V <sub>GS</sub> = 16 V,	V <sub>DS</sub> = 0		10	100	nA
IGSSR	Reverse-gate current, drain short circuited to source	V <sub>SG</sub> = 16 V,	V <sub>DS</sub> = 0		10	100	nA
1	Leakage current, V <sub>DD3</sub> -to-GND,	V= 46.V	T <sub>C</sub> = 25°C		0.05	1	^
likg	gate shorted to source	V <sub>DGND</sub> = 16 V	T <sub>C</sub> = 125°C		0.5	10	μΑ
	Static drain-to-source on-state resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.3 A,	T <sub>C</sub> = 25°C		0.35	0.39	
r <sub>DS(on)</sub>		See Notes 3 and 4 and Figure 10	T <sub>C</sub> = 125°C		0.5	0.56	Ω
-DS(0H)	otatio drain to occide on otate resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A,	T <sub>C</sub> = 25°C		0.4	0.45	22
		See Notes 3 and 4 and Figures 8 and 10	T <sub>C</sub> = 125°C		0.56	0.65	
		$V_{DS} = 14 V,$	$I_D = 500 \text{ mA},$	0.3	0.8		
9fs	Forward transconductance	See Notes 3 and 4					s
0		V <sub>DS</sub> = 14 V, See Notes 3 and 4 and	I <sub>D</sub> = 750 mA, d Figure 14	0.4	0.93		
C <sub>iss</sub>	Short-circuit input capacitance, common source				96		
C <sub>oss</sub>	Short-circuit output capacitance, common source	V <sub>DS</sub> = 14 V, f = 1 MHz,	V <sub>GS</sub> = 0, See Figure 18		98		pF
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source				65		

NOTES: 3. Technique should limit  $T_J - T_C$  to 10°C maximum.

4. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.



## TPIC1501A QUAD AND HEX POWER DMOS ARRAY

SLIS046A - MAY 1995 - REVISED JUNE 1996

## source-to-drain diode characteristics, Q3A, Q4A, Q5A, $T_C = 25^{\circ}C$

	PARAMETER	TEST CON	MIN	TYP	MAX	UNIT	
t <sub>rr</sub>	Reverse-recovery time	Is = 750 mA,	$V_{GS} = 0$ , di/dt = 100 A/ $\mu$ s,		60		ns
Q <sub>RR</sub>	Total diode charge	V <sub>DS</sub> = 14 V, See Figures 2 and 23		55		nC	
t <sub>rr</sub>	Reverse-recovery time	I <sub>S</sub> = 1.5 A,	V <sub>GS</sub> = 0,		120		ns
Q <sub>RR</sub>	Total diode charge	$V_{DS} = 14 V$ ,	$di/dt = 100 A/\mu s$		150		nC

# resistive-load switching characteristics, Q3A, Q3B, Q4A, Q4B, Q5A, Q5B, $T_C$ = 25°C

	PARAMETER	TEST CONDITIONS				TYP	MAX	UNIT
<sup>t</sup> d(on)	Turn-on delay time					18		
<sup>t</sup> d(off)	Turn-off delay time	V <sub>DD</sub> = 14 V, R <sub>I</sub>	_ = 18.7 Ω,	t <sub>en</sub> = 10 ns,		25		ns
t <sub>r</sub>	Rise time	t <sub>dis</sub> = 10 ns, See Figure 3				13		115
t <sub>f</sub>	Fall time					20		
Qg	Total gate charge					1.6	2	
Q <sub>gs(th)</sub>	Threshold gate-to-source charge	V <sub>DS</sub> = 14 V, I <sub>D</sub> See Figure 4	$V_{DS} = 14 \text{ V},  I_{D} = 750 \text{ mA},  V_{GS} = 10 \text{ V},$				0.32	nC
Q <sub>gd</sub>	Gate-to-drain charge	See Figure 4				0.42	0.52	
L(drain)	Internal drain inductance					5		nH
L <sub>(source)</sub>	Internal source inductance		·			5		шп
r(gate)	Internal gate resistance		·			0.25		Ω

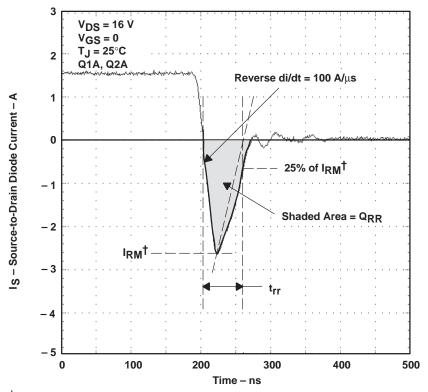
### thermal resistance

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	See Notes 5 and 8		90		
$R_{\theta JB}$	Junction-to-board thermal resistance	See Notes 6 and 8		38		°C/W
$R_{\theta JP}$	Junction-to-pin thermal resistance	See Notes 7 and 8		28		

NOTES: 5. Package is mounted on a FR4 printed-circuit board with no heat sink.

- 6. Package is mounted on a 24 in<sup>2</sup>, 4-layer FR4 printed-circuit board.
- 7. Package is mounted in intimate contact with infinite heat sink.
- 8. All outputs have equal power.

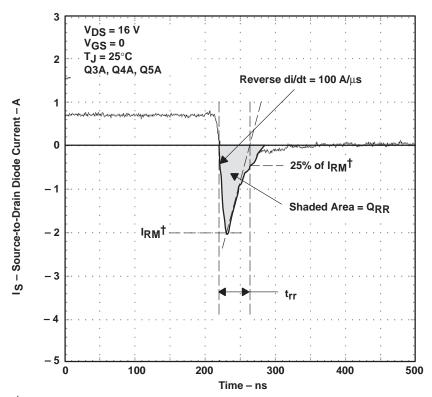
### PARAMETER MEASUREMENT INFORMATION



† I<sub>RM</sub> = maximum recovery current

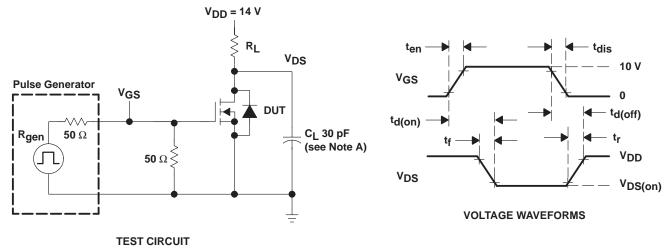
Figure 1. Reverse-Recovery-Current Waveform of Source-to-Drain Diodes

### PARAMETER MEASUREMENT INFORMATION



† I<sub>RM</sub> = maximum recovery current

Figure 2. Reverse-Recovery-Current Waveform of Source-to-Drain Diodes



NOTE A: C<sub>L</sub> includes probe and jig capacitance.

Figure 3. Resistive-Switching Test Circuit and Voltage Waveforms



### PARAMETER MEASUREMENT INFORMATION

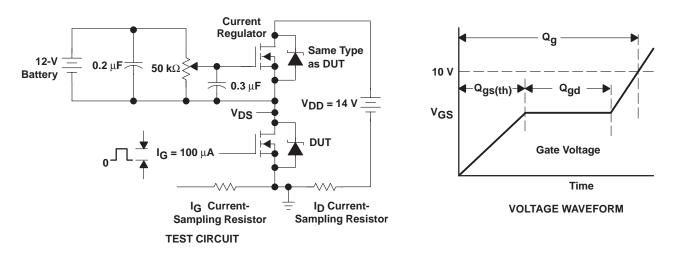
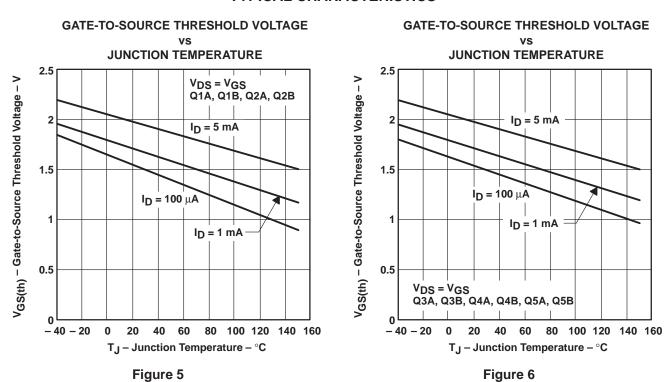
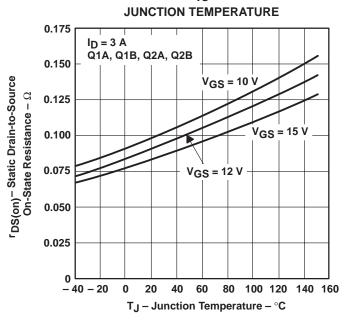


Figure 4. Gate-Charge Test Circuit and Voltage Waveform

### **TYPICAL CHARACTERISTICS**



#### STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE



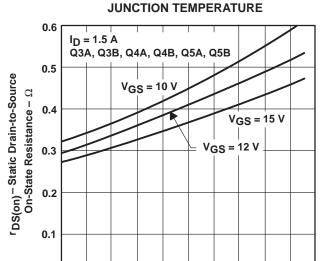


Figure 7

Figure 8

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

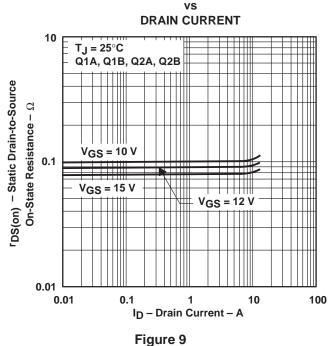
60

T<sub>J</sub> - Junction Temperature - °C

80 100 120 140 160

10

## STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE



**DRAIN CURRENT** 0.9 T<sub>J</sub> = 25°C 0.8 Q3A, Q3B, Q4A 0.7 Q4B, Q5A, Q5B 'DS(on) - Static Drain-to-Source 0.6 On-State Resistance –  $\Omega$ V<sub>GS</sub> = 12 V 0.5 V<sub>GS</sub> = 10 V 0.4 0.3  $V_{GS} = 15 V$ 

20 40

-40 - 20

Figure 10

ID - Drain Current - A

0.2

0.1

0.01

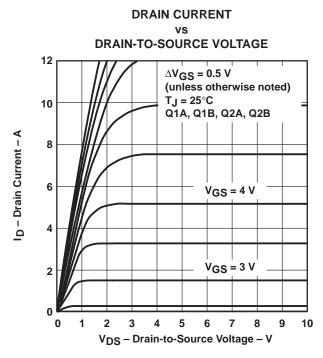


Figure 11

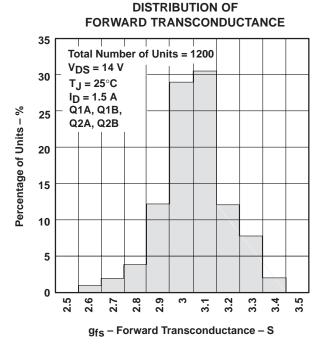


Figure 13

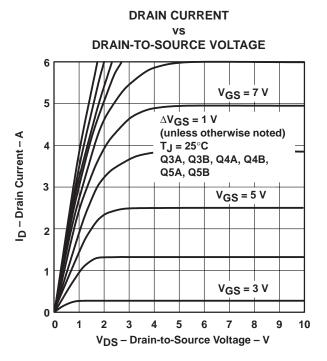


Figure 12

# DISTRIBUTION OF FORWARD TRANSCONDUCTANCE

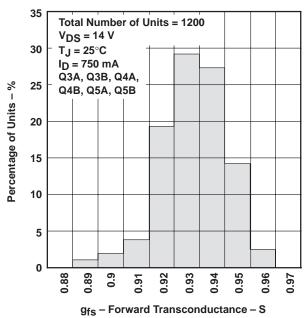


Figure 14

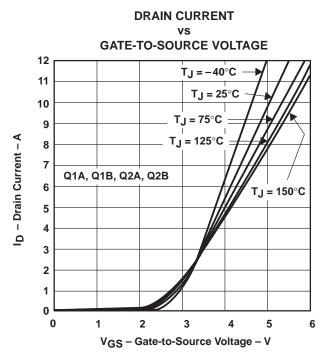


Figure 15

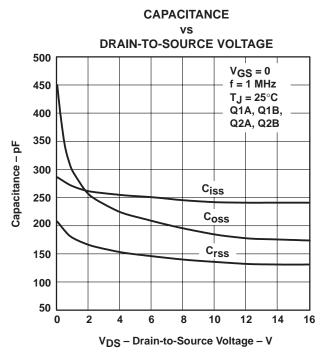


Figure 17

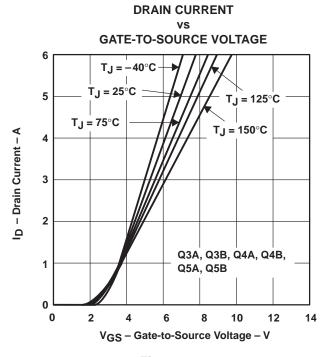


Figure 16

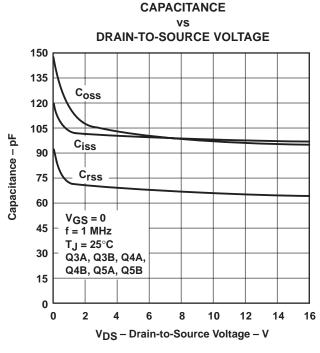


Figure 18



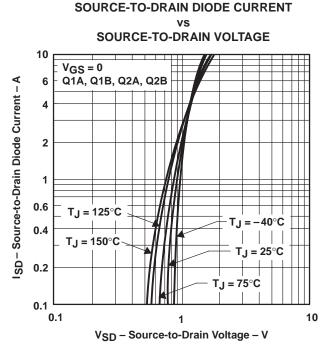


Figure 19

**DRAIN-TO-SOURCE VOLTAGE AND** 

**GATE-TO-SOURCE VOLTAGE** 

### VS **GATE CHARGE** 16 16 $I_D = 1.5 A$ TJ = 25°C 14 14 Q1A, Q1B, Q2A, Q2B V<sub>DS</sub> – Drain-to-Source Voltage – V See Figure 4 VGS - Gate-to-Source Voltage -12 12 $V_{DD} = 10 V$ 10 10 8 8 6 6 $V_{DD} = 12 V$ $V_{DD} = 14 \text{ V}$ 2 2 V<sub>DD</sub> = 12 V 0 0 7 0 1 2 4 5 6

Q<sub>g</sub> – Gate Charge – nC Figure 21

SOURCE-TO-DRAIN DIODE CURRENT vs SOURCE-TO-DRAIN VOLTAGE

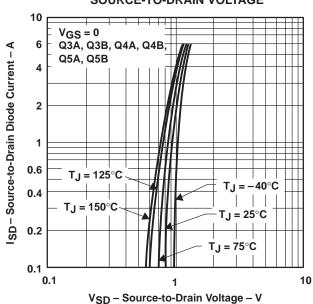


Figure 20

# DRAIN-TO-SOURCE VOLTAGE AND GATE-TO-SOURCE VOLTAGE

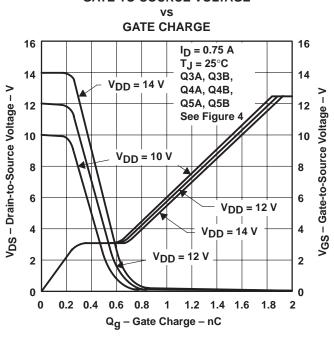


Figure 22

# REVERSE RECOVERY TIME vs

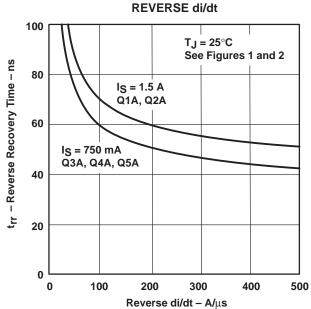


Figure 23

### THERMAL INFORMATION

# MAXIMUM DRAIN CURRENT vs

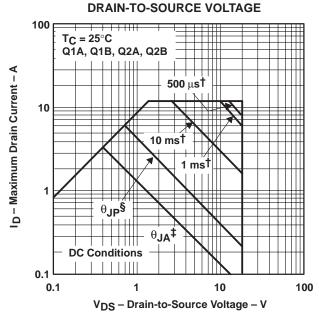


Figure 24

# MAXIMUM DRAIN CURRENT vs

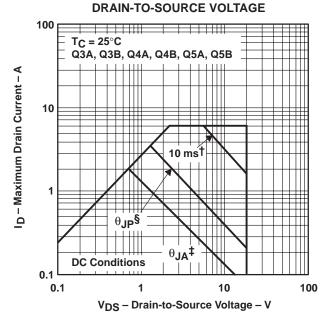


Figure 25

<sup>†</sup>Less than 10% duty cycle

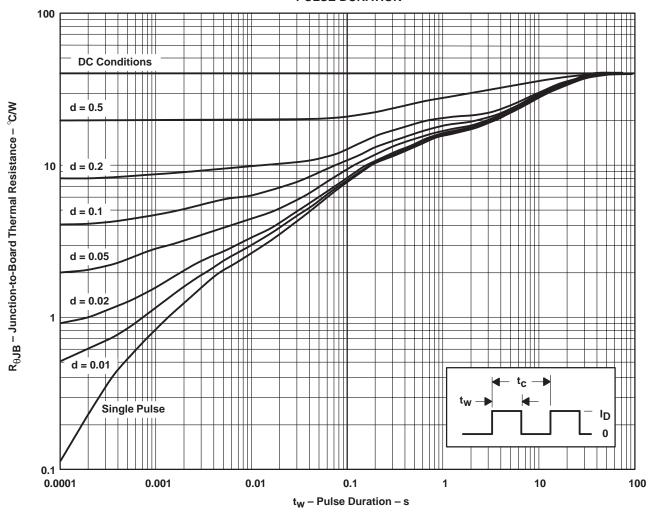
<sup>&</sup>lt;sup>‡</sup> Device is mounted on a 24 in<sup>2</sup>, 4 layer FR4 printed-circuit board.

<sup>§</sup> Device is mounted in intimate contact with infinite heat sink.

### THERMAL INFORMATION

# DW PACKAGE† JUNCTION-TO-BOARD THERMAL RESISTANCE

PULSE DURATION



† Device is mounted on 24 in<sup>2</sup>, 4-layer FR4 printed-circuit board with no heat sink.

 $\begin{aligned} \text{NOTE A:} \quad Z_{\theta B}(t) &= r(t) \; R_{\theta JB} \\ t_W &= \text{pulse duration} \\ t_C &= \text{cycle time} \\ d &= \text{duty cycle} = t_W/t_C \end{aligned}$ 

Figure 26





## PACKAGE OPTION ADDENDUM

2-Apr-2012

### **PACKAGING INFORMATION**

Orderable Device	Status (1) F	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
TPIC1501ADW	OBSOLETE	SOIC	DW	24		TBD	Call TI	Call TI	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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DW (R-PDSO-G24)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



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